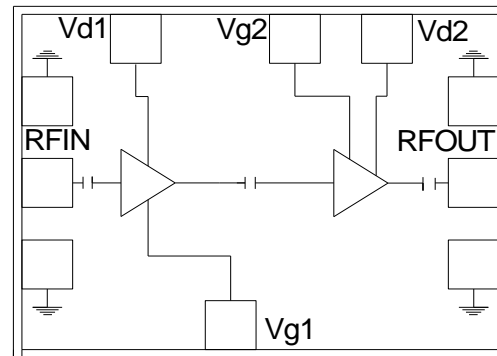


5.0 – 6.0 GHz 1 Watt Power Amplifier

Features

- ◆ Frequency Range : 5.0 – 6.0 GHz
- ◆ 32 dBm Psat
- ◆ 22 dB Power gain
- ◆ 35% PAE
- ◆ High IP3
- ◆ Input Return Loss > 10 dB
- ◆ Output Return Loss > 14 dB
- ◆ Dual bias operation
- ◆ No external matching required
- ◆ DC decoupled input and output
- ◆ 0.5 μ m InGaAs pHEMT Technology
- ◆ Chip dimension: 1.8 x 1.6 x 0.1 mm

Functional Diagram



Typical Applications

- ◆ RADAR
- ◆ Military & space
- ◆ LMDS, VSAT

Description

The ASL4003 is a C-band Power amplifier with 32 dBm power output. The PA uses 2 stages of amplification and operates in 5.0 – 6.0 GHz frequency range. The PA features 22 dB of gain with input and output return losses of 10dB and 15 dB respectively. The PA has a high IP3 of 40dBm and 35% PAE. This feature enables it to be used in the applications requiring efficiency along with linearity. The chip operates with dual bias supply voltage. The die is fabricated using a reliable 0.5 μ m InGaAs pHEMT technology. The Circuit grounds are provided through vias to the backside metallization.

Absolute Maximum Ratings ⁽¹⁾

| Parameter | Absolute Maximum | Units |
|--------------------------------|------------------|-------|
| Drain bias voltage (Vd) | +10 | volts |
| Drain current (Id) | 0.6 | A |
| RF input power (RFin at Vd=9V) | 30 | dBm |
| Operating temperature | -50 to +85 | °C |
| Storage Temperature | -65 to +150 | °C |

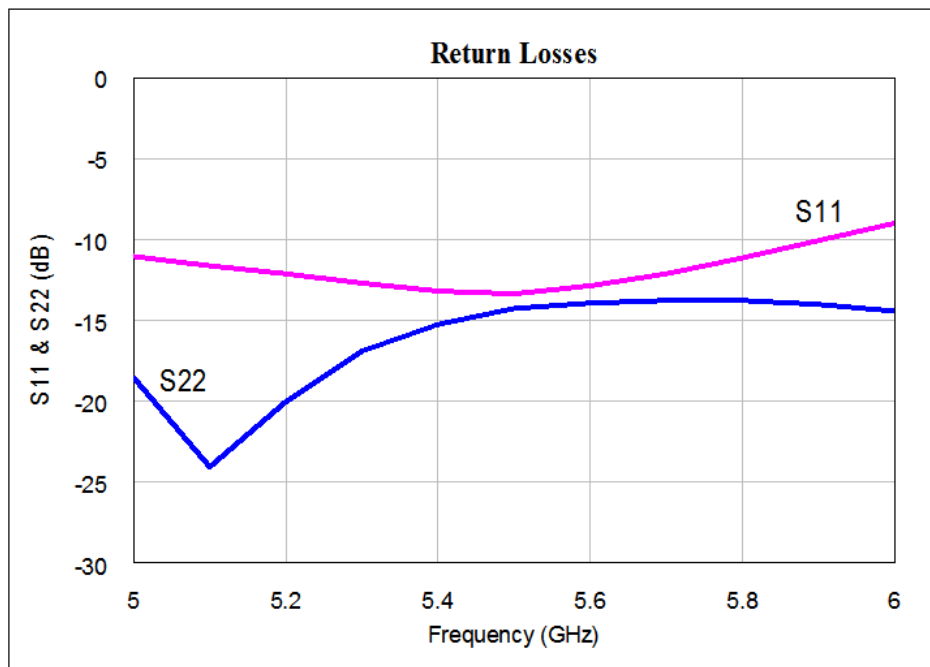
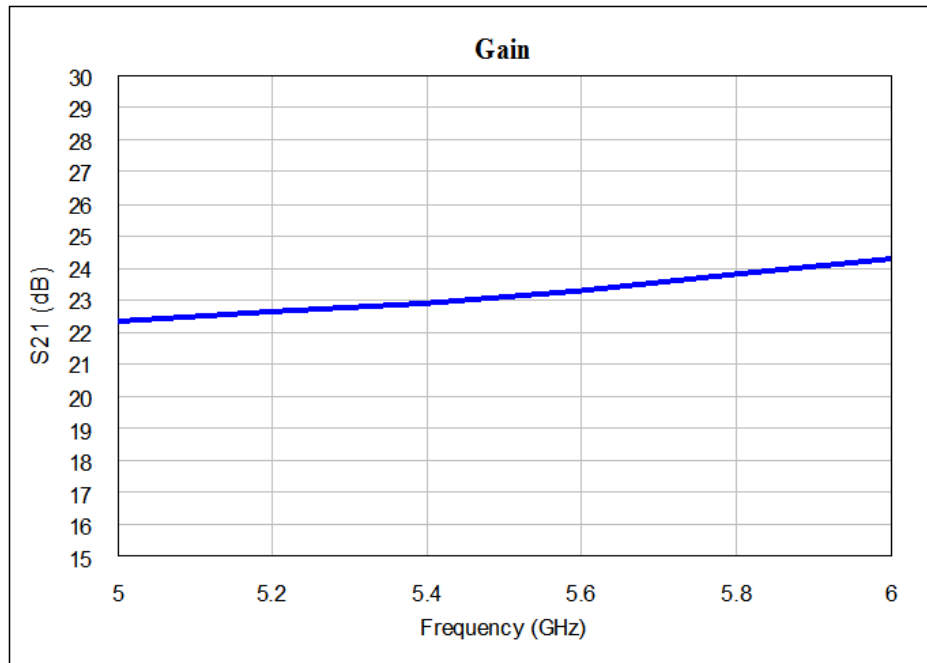
1. Operation beyond these limits may cause permanent damage to the component

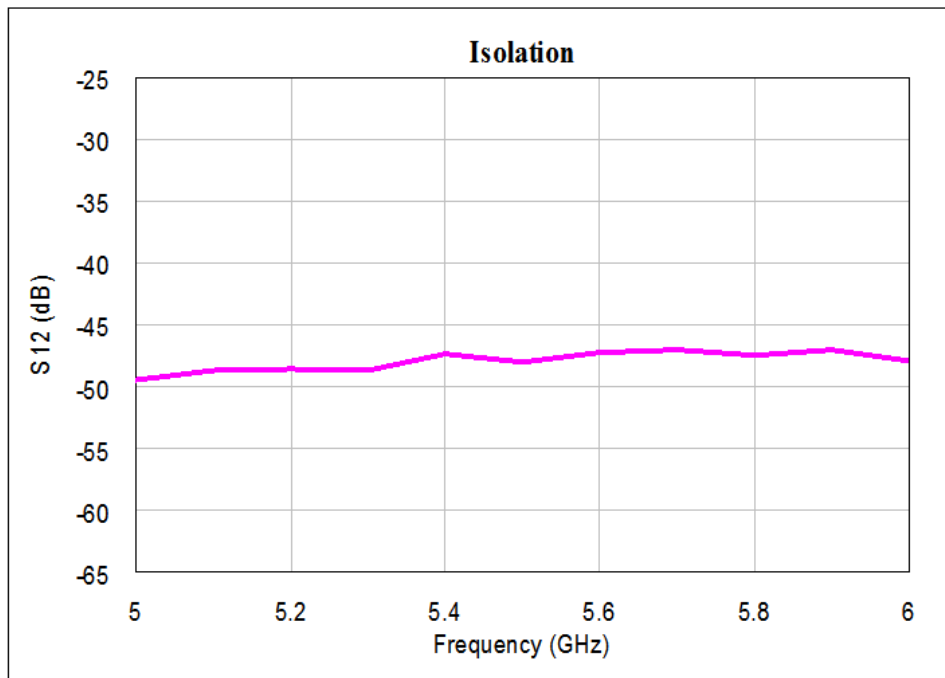
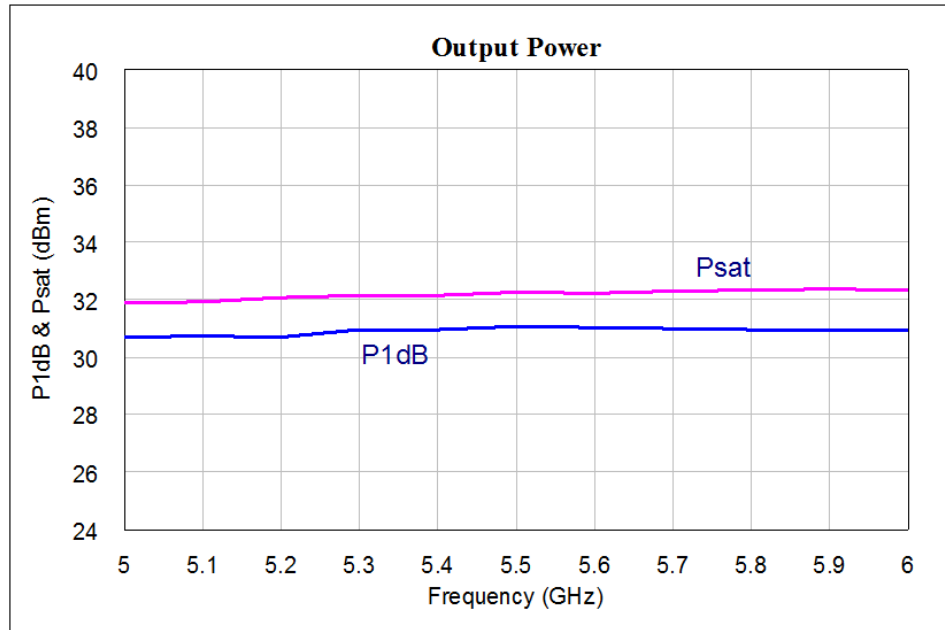
Electrical Specifications ⁽¹⁾ @ T_A = 25 °C, V_{d1} = V_{d2} = 8V, V_{g1} = V_{g2} = -1V
Z_o = 50 Ω

| Parameter | Typ. | Units |
|---|-----------|-------|
| Frequency Range | 5.0 – 6.0 | GHz |
| Gain | 22 | dB |
| Gain Flatness | +/-1 | dB |
| Output Power (P1 dB) | 31 | dBm |
| Input Return Loss | 10 | dB |
| Output Return Loss | 14 | dB |
| Saturated output power (P _{sat}) | 32 | dBm |
| Output Third Order Intercept (IP3) | 40 | dBm |
| Power Added Efficiency (PAE) | 35% | -- |
| Supply Current(I _{dq}) | 330 | mA |
| Supply Current(I _{dsat} ²) | 450 | mA |

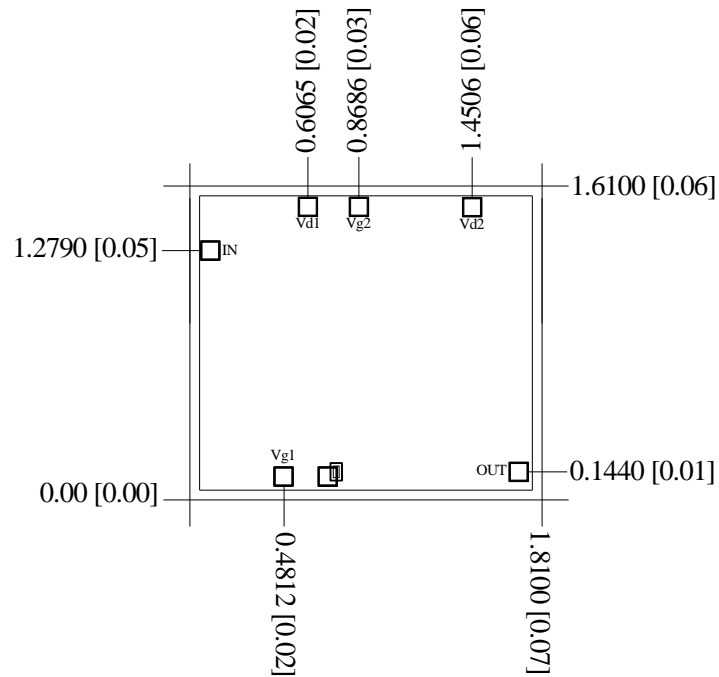
Note:

1. Electrical specifications as measured in test fixture.
2. I_{dsat} is the maximum current under input RF drive condition.

Test fixture data
 $V_{d1} = V_{d2} = 8V$, $V_{g1} = V_{g2} = -1V$, Total Current (I_{dq}) = 330mA, $T_A = 25^\circ C$


Test fixture data
 $V_{d1} = V_{d2} = 8V$, $V_{g1} = V_{g2} = -1V$, Total Current (I_{dq}) = 330mA, $T_A = 25^\circ C$


Bond Pad Locations

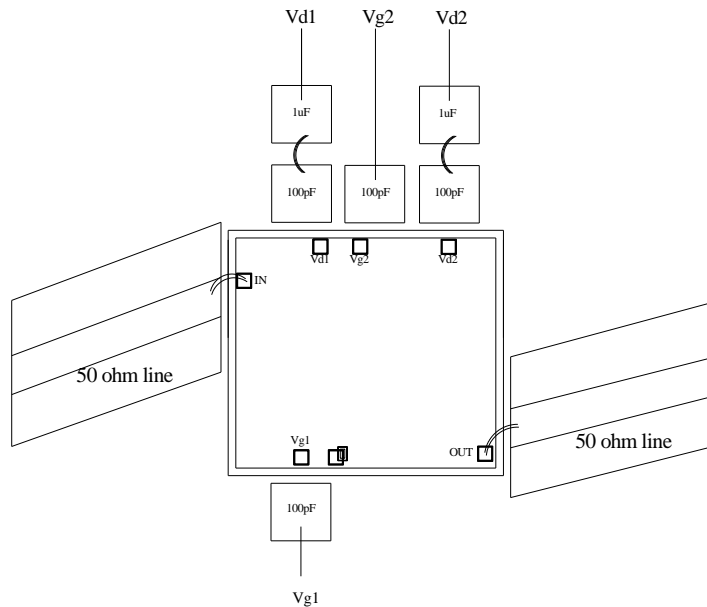


Units: millimeters (inches)

Note:

1. All RF and DC bond pads are 100 μ m x 100 μ m
2. Pad no. 1 : IN (RF Input)
3. Pad no. 2 : Vd1 (1st Stage Drain Voltage).
4. Pad no. 3 : Vg2 (2nd Stage Gate Voltage).
5. Pad no. 4 : Vd2 (2nd Stage Drain Voltage).
6. Pad no. 5 : Out (RF Output).
7. Pad no. 6 : Vg1 (1st Stage Gate Voltage).
8. All the dimensions shown above are measured taking bottom left corner as reference.

Recommended Assembly Diagram



Note :

1. Two 1 mil (0.0254mm) bond wires of minimum length should be used for RF input and output.
2. Two 1 mil (0.0254mm) bond wires of minimum length should be used from chip bond pad to 100pF Single Layer Bypass Capacitors.
3. Input and output 50 ohm lines are on 5 mil RT Duroid substrate.
4. 1uF capacitors can be additionally used for effective bypass.
5. The RF input & output ports are DC decoupled on-chip.
7. Proper heat sink like Copper tungsten or copper molybdenum to be used for better reliability of chip.

Die attach: For Epoxy attachment, use of a two-component conductive epoxy is recommended. An epoxy fillet should be visible around the total die periphery. If Eutectic attachment is preferred, use of fluxless AuSn (80/20) 1-2 mil thick preform solder is recommended. Use of AuGe preform should be strictly avoided.

Wire bonding: For DC pad connections use either ball or wedge bonds. For best RF performance, use of 150 - 200µm length of wedge bonds is advised. Single Ball bonds of 250-300µm though acceptable, may cause a deviation in RF performance.



GaAs MMIC devices are susceptible to Electrostatic discharge. Proper precautions should be observed during handling, assembly & testing

All information and Specifications are subject to change without prior notice